

Max r<sub>DS(on)</sub> = 2.8 mΩ at V<sub>GS</sub> = 10 V, I<sub>D</sub> = 24 A

Max r<sub>DS(on)</sub> = 3.3 mΩ at V<sub>GS</sub> = 4.5 V, I<sub>D</sub> = 22 A

N-Channel PowerTrench<sup>®</sup> SyncFET<sup>TM</sup>

**FAIRCHILD** 

**FDMS8570S** 

**25 V, 60 A, 2.8 m**Ω

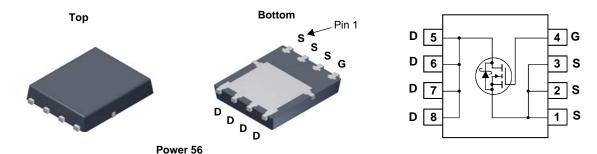
Features

# **General Description**

This N-Channel SyncFET<sup>TM</sup> is produced using Fairchild Semiconductor's advanced PowerTrench<sup>®</sup> process. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{DS(on)}$  while maintaining excellent switching performance by extremely low Junction-to-Ambient thermal resistance. This device has the added benefit of an efficient monolithic Schottky body diode.

### Applications

- Synchronous Rectifier for DC/DC Converters
- Telecom Secondary Side Rectification
- High End Server/Workstation Vcore Low Side



# MOSFET Maximum Ratings T<sub>A</sub> = 25°C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V <sub>DS</sub>	Drain to Source Voltage			25	V	
V <sub>GS</sub>	Gate to Source Voltage			12	V	
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		60		
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	24	Α	
	-Pulsed			100		
E <sub>AS</sub>	Single Pulse Avalanche Energy		(Note 3)	45	mJ	
P <sub>D</sub>	Power Dissipation	T <sub>C</sub> = 25 °C		48	w	
	Power Dissipation $T_A = 25 \degree C$ (Note 1a)		(Note 1a)	2.5	vv	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Ra	ange		-55 to +150	°C	

## **Thermal Characteristics**

$R_{\thetaJC}$	Thermal Resistance, Junction to Case	T <sub>C</sub> = 25 °C	2.6	°C/W
$R_{ ext{ heta}JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/VV

# Package Marking and Ordering Information

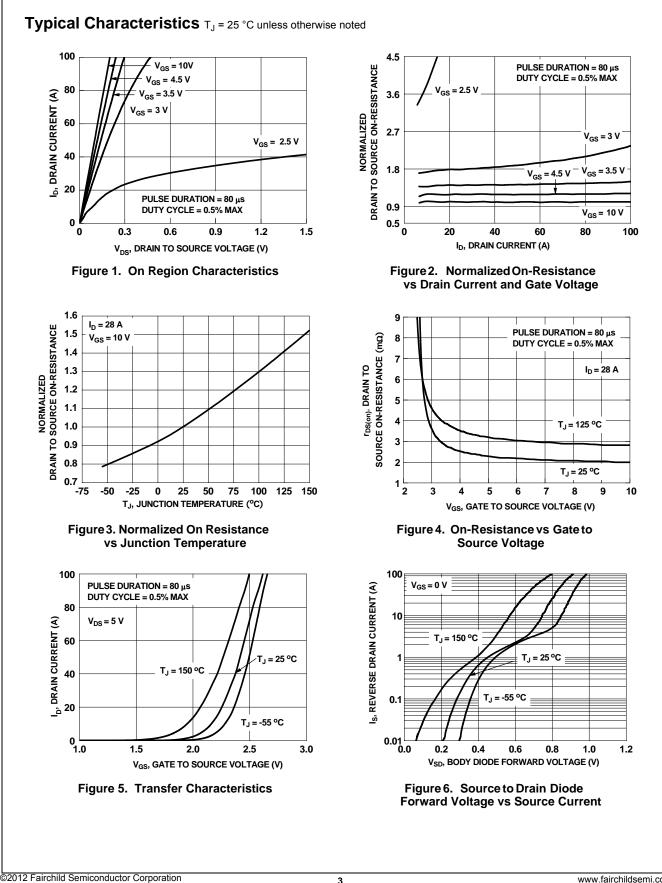
Device Marking	Device	Package	Reel Size	Tape Width	Quantity
10OD	FDMS8570S	Power 56	13"	12 mm	3000 units

	Test Conditions	Min	Тур	Max	Units
istics					
in to Source Breakdown Voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0 V	25			V
akdown Voltage Temperature	$I_D$ = 10 mA, referenced to 25 °C		23		mV/°C
o Gate Voltage Drain Current	V <sub>DS</sub> = 20 V, V <sub>GS</sub> = 0 V			500	μA
e to Source Leakage Current	$V_{GS}$ = +12 V/-8 V, $V_{DS}$ = 0 V			±100	nA
istics					
	$V_{GS} = V_{DS}$ , $I_{D} = 1 \text{ mA}$	1.1	1.5	2.2	V
e to Source Threshold Voltage	$I_D = 10$ mA, referenced to 25 °C		-3		mV/°C
<u>.</u>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 24 A		2.1	2.8	
ic Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 22 \text{ A}$		2.4	3.3	mΩ
	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 24 A, T <sub>J</sub> = 125 °C		2.9	3.9	+
ward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 24 A		215		S
racteristics					
			2825		pF
	V <sub>DS</sub> = 13 V, V <sub>GS</sub> = 0 V,				pF
	f = 1 MHz				pF
e Resistance			0.8		Ω
aractoristics					
			11		
					ns
					ns
	-				ns
	$\gamma = 0 \gamma t_0 10 \gamma t_0$				ns nC
					nC
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=					nC
-			4.4		lic
Diode Characteristics			11		1
rce to Drain Diode Forward Voltage					v
-	$V_{GS} = 0 V, I_S = 24 A$ (Note 2)			1.2	
	– I <sub>F</sub> = 24 A, di/dt = 300 A/μs				ns
erse Recovery Charge			19		nC
	e to Source Leakage Current istics e to Source Threshold Voltage e to Source Threshold Voltage apperature Coefficient ic Drain to Source On Resistance ward Transconductance racteristics ut Capacitance put Capacitance rerse Transfer Capacitance e Resistance aracteristics n-On Delay Time e Time al Gate Charge e to Source Gate Charge e to Source Gate Charge e to Drain "Miller" Charge Diode Characteristics arce to Drain Diode Forward Voltage rerse Recovery Time rerse Recovery Charge	e to Source Leakage Current $V_{GS} = +12 \text{ V}/-8 \text{ V}, V_{DS} = 0 \text{ V}$ isticse to Source Threshold Voltage to Source Threshold Voltage uperature Coefficient $V_{GS} = V_{DS}, I_D = 1 \text{ mA}$ $I_D = 10 \text{ mA}, referenced to 25 °Cvic Drain to Source On ResistanceV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}vic Drain to Source On ResistanceV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}vic AracteristicsV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}aracteristicsV_{DS} = 5 \text{ V}, I_D = 24 \text{ A}ut Capacitanceput Capacitancererse Transfer CapacitanceV_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V},f = 1 MHzf = 1 MHze Resistancef = 1 MHzaracteristicsn-On Delay Timea Timeal Gate ChargeV_{GS} = 0 \text{ V to } 10 \text{ V}V_{GS} = 0 \text{ V to } 10 \text{ V}I_D = 24 \text{ A}d Gate Chargee to Source Gate ChargeV_{GS} = 0 \text{ V to } 10 \text{ V}I_D = 24 \text{ A}Diode Characteristicsarce to Drain Diode Forward VoltageV_{GS} = 0 \text{ V}, I_S = 2 \text{ A} (Note 2)V_{GS} = 0 \text{ V}, I_S = 24 \text{ A} (Note 2)rerse Recovery Timeerse Recovery ChargeI_F = 24 \text{ A}, di/dt = 300 \text{ A}/\mus$	e to Source Leakage Current $V_{GS} = +12 \text{ V}/-8 \text{ V}, V_{DS} = 0 \text{ V}$ isticse to Source Threshold Voltage toperature Coefficient $V_{GS} = V_{DS}, I_D = 1 \text{ mA}$ 1.1 $I_D = 10 \text{ mA}, referenced to 25 °CV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}vic Drain to Source On ResistanceV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}V_{GS} = 10 \text{ V}, I_D = 24 \text{ A}, T_J = 125 °Cward TransconductanceV_{DS} = 5 \text{ V}, I_D = 24 \text{ A}racteristicsut Capacitanceput CapacitanceV_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V},f = 1 MHze Resistancearacteristicsn-On Delay Timea Timeof Gate ChargeV_{GS} = 0 \text{ V to } 10 \text{ V}al Gate ChargeV_{GS} = 0 \text{ V to } 4.5 \text{ V}bi Gate ChargeV_{GS} = 0 \text{ V to } 4.5 \text{ V}bi Dode Characteristicsrice to Drain Diode Forward VoltageV_{GS} = 0 \text{ V}, I_S = 2 \text{ A} (Note 2)rese Recovery Timererse Recovery ChargeI_F = 24 \text{ A}, di/dt = 300 \text{ A}/\mus$	e to Source Leakage Current $V_{GS} = +12 \text{ V/-8 V}, V_{DS} = 0 \text{ V}$ isticse to Source Threshold Voltage pperature Coefficient $V_{GS} = V_{DS}, I_D = 1 \text{ mA}$ 1.11.5 $I_D = 10 \text{ mA}, referenced to 25 °C-3pperature CoefficientI_D = 10 \text{ mA}, referenced to 25 °C-3ic Drain to Source On ResistanceV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}2.1ward TransconductanceV_{GS} = 10 \text{ V}, I_D = 24 \text{ A}2.1vare TransconductanceV_{DS} = 5 \text{ V}, I_D = 24 \text{ A}2.15racteristicsut Capacitanceput CapacitanceV_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V},662rerse Transfer Capacitancef = 1 \text{ MHz}94e Resistance0.833aracteristics11a TimeV_{DS} = 13 \text{ V}, I_D = 24 \text{ A},4n-On Delay TimeV_{GS} = 0 \text{ V to 10 V}42al Gate ChargeV_{GS} = 0 \text{ V to 10 V}42al Gate ChargeV_{GS} = 0 \text{ V to 10 V}42to Source Gate ChargeV_{GS} = 0 \text{ V to 4.5 V}V_{DD} = 13 \text{ V},to train "Miller" ChargeV_{GS} = 0 \text{ V}, I_S = 2 \text{ A}(Note 2)0.6Diode Characteristicstrace to Drain Diode Forward VoltageV_{GS} = 0 \text{ V}, I_S = 2 \text{ A}(Note 2)0.8trace to Drain Diode Forward VoltageV_{GS} = 0 \text{ V}, I_S = 2 \text{ A}(Note 2)0.8trace to Drain Diode Forward VoltageV_{GS} = 0 \text{ V}, I_S = 2 \text{ A}(Note 2)0.8trace to Drain Diode Forwar$	e to Source Leakage Current $V_{GS} = +12 \ V/-8 \ V, \ V_{DS} = 0 \ V$ ±100    istics  e to Source Threshold Voltage $V_{GS} = V_{DS}, \ I_D = 1 \ mA$ 1.1  1.5  2.2    e to Source Threshold Voltage $I_D = 10 \ mA, \ referenced \ to 25 \ °C$ -3  -3  -3    ic Drain to Source On Resistance $V_{GS} = 10 \ V, \ I_D = 24 \ A$ 2.1  2.8  -3    ward Transconductance $V_{DS} = 10 \ V, \ I_D = 24 \ A, \ T_J = 125 \ °C$ 2.9  3.9    ward Transconductance $V_{DS} = 5 \ V, \ I_D = 24 \ A$ 2.15  -3    racteristics

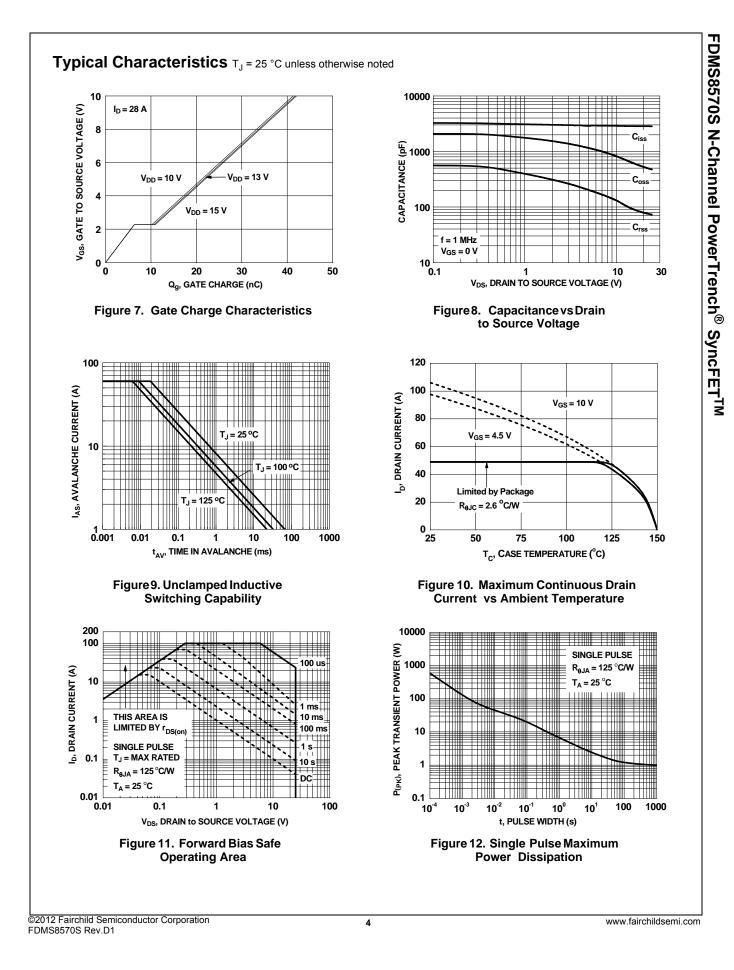
2. Pulse Test: Pulse Width < 300  $\mu$ s, Duty cycle < 2.0%. 3. E<sub>AS</sub> of 45 mJ is based on starting T<sub>J</sub> = 25 °C, L = 0.4 mH, I<sub>AS</sub> = 15 A, V<sub>DD</sub> = 23 V, V<sub>GS</sub> = 10 V. 100% test at L = 0.1 mH, I<sub>AS</sub> = 23.8 A.

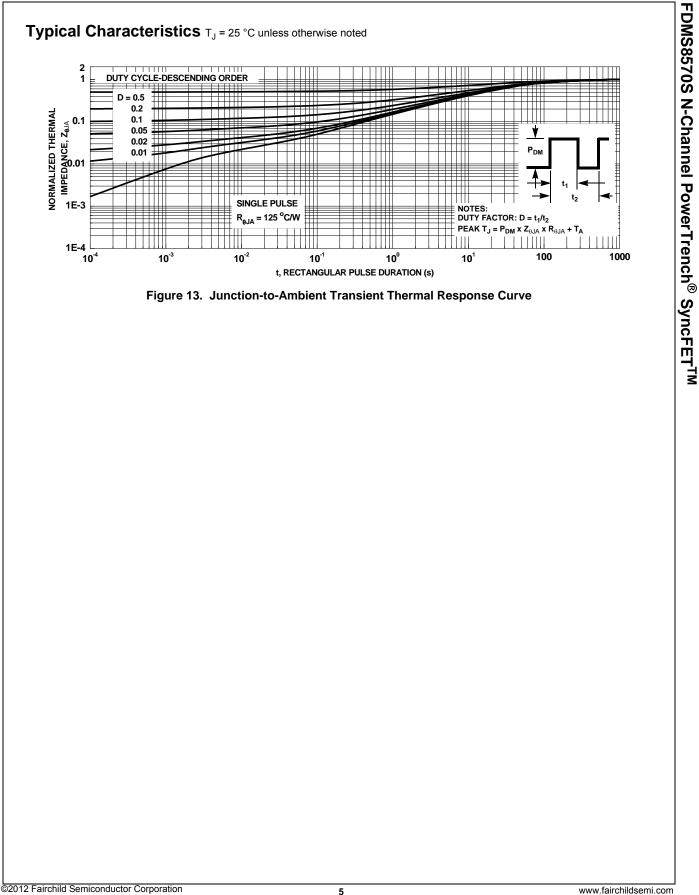
Electrical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

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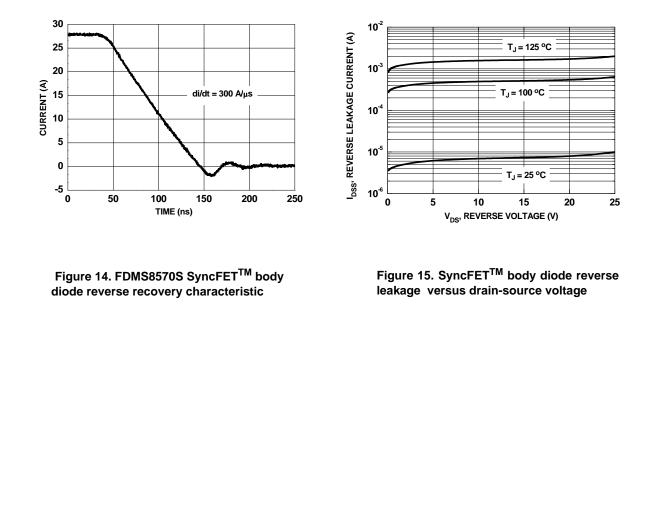
# FDMS8570S N-Channel PowerTrench<sup>®</sup> SyncFET<sup>TM</sup>

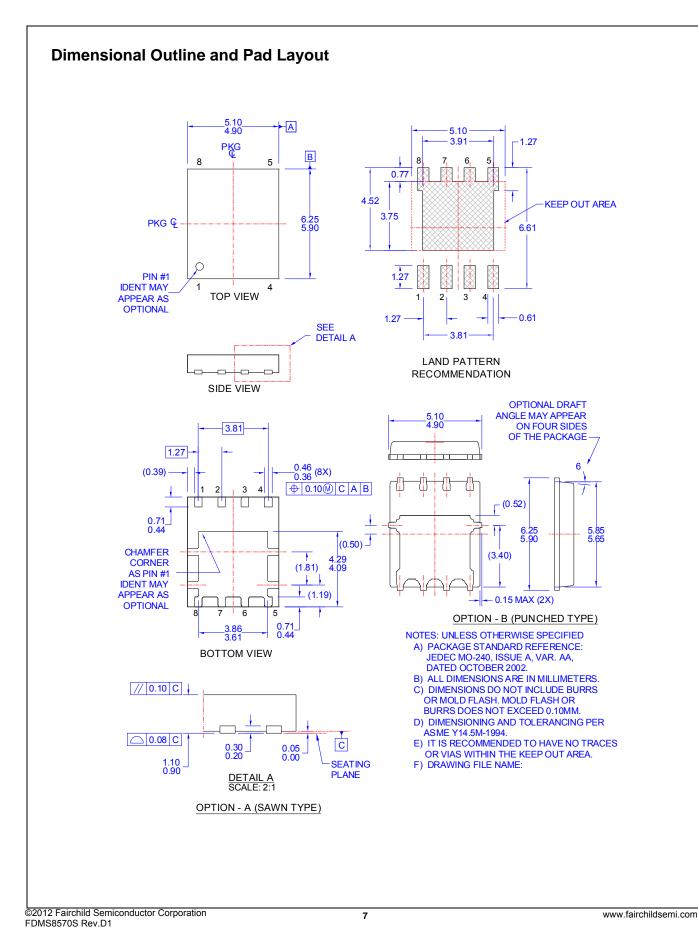
# Typical Characteristics (continued)

## SyncFET<sup>™</sup> Schottky body diode Characteristics

Fairchild's SyncFET<sup>TM</sup> process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 14 shows the reverse recovery characteristic of the FDMS8570S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.





FDMS8570S N-Channel PowerTrench<sup>®</sup> SyncFET<sup>TM</sup>



SEMICONDUCTOR

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